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Network aware time management and event distribution.

George F. Riley, Richard Fujimoto, Mostafa H. Ammar

May 2000 Proceedings of the fourteenth workshop on Parallel and distributed simulation

Full text available: pdf(794.39 KB)

Additional Information: full citation, abstract, references, citings, index

In this paper we discuss new synchronization algorithms for Parallel and Distributed Discrete Event Simulations (PDES) which exploit the capabilities and behavior of the underlying communications network. Previous work in this areas has assumed the network to be a Black Box which provides a one-to-one, reliable and in-order message passing paradigm. In our work, we utilize the Broadcast capability of the ubiquitous Ethernet for sync ...

2 Fault-tolerant wait-free shared objects

Prasad Jayanti, Tushar Deepak Chandra, Sam Toueg May 1998 Journal of the ACM (JACM), Volume 45 Issue 3

Full text available: pcif(393.60 KB)

Additional Information: full opation, abstract, references, citings, index terms

Wait-free implementations of shared objects tolerate the failure of processes, but not the failure of base objects from which they are implemented. We consider the problem of implementing shared objects that tolerate the failure of both processes and base objects. We identify two classes of object failures: responsive and nonresponsive. With responsive failures, a faulty object responds to every operation, but its responses may be incorrect. With ...

Keywords: MIMD, asynchronous computing, fault-tolerance, implementation, shared memory, shared objects, synchronization

Formal verification in hardware design: a survey

Christoph Kern, Mark R. Greenstreet

April 1999 ACM Transactions on Design Automation of Electronic Systems (TODAES). Volume 4 Issue 2

Full text available: pcf(411.53 KB)

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In recent years, formal methods have emerged as an alternative approach to ensuring the quality and correctness of hardware designs, overcoming some of the limitations of traditional validation techniques such as simulation and testing. There are two main aspects to the application of formal methods in a design process: the formal framework used to specify desired properties of a design and the verification techniques and tools used to reason about the relationship between a spec ...



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